

Notice of References Cited	Application/Control No. 10/534,931		Applicant(s)/Patent Under Reexamination LI, SHUNPU	
	Examiner DAVID N. BROWN II		Art Unit 1791	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,512,848 A	04-1985	Deckman et al.	216/43
*	B	US-5,512,131 A	04-1996	Kumar et al.	438/738
*	C	US-5,948,470 A	09-1999	Harrison et al.	427/198
*	D	US-6,030,556 A	02-2000	DePuydt et al.	264/1.37
*	E	US-6,323,108 B1	11-2001	Kub et al.	438/458
*	F	US-2002/0005391 A1	01-2002	Schaffer et al.	216/41
*	G	US-6,365,059 B1	04-2002	Pechenik, Alexander	216/52
*	H	US-2002/0042027 A1	04-2002	Chou et al.	430/322
*	I	US-2002/0094496 A1	07-2002	Choi et al.	430/322
*	J	US-2002/0115002 A1	08-2002	Bailey et al.	430/5
*	K	US-2002/0168592 A1	11-2002	Vezenov et al.	430/320
*	L	US-2003/0205657 A1	11-2003	Voisin, Ronald D.	249/187.1
*	M	US-2003/0205658 A1	11-2003	Voisin, Ronald D.	249/187.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/534,931		Applicant(s)/Patent Under Reexamination LI, SHUNPU	
	Examiner DAVID N. BROWN II		Art Unit 1791	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0053009 A1	03-2004	Ozin et al.	428/168
*	B	US-2004/0053146 A1	03-2004	Sreenivasan et al.	430/022
*	C	US-2004/0086793 A1	05-2004	Sreenivasan et al.	430/022
*	D	US-6,753,130 B1	06-2004	Liu et al.	430/313
*	E	US-6,755,984 B2	06-2004	Lee et al.	216/54
*	F	US-2004/0124566 A1	07-2004	Sreenivasan et al.	264/494
*	G	US-2004/0141168 A1	07-2004	Sreenivasan et al.	355/075
*	H	US-2004/0170925 A1	09-2004	Roach et al.	430/281.1
*	I	US-2004/0247732 A1	12-2004	Walk, Michael	425/385
*	J	US-2005/0221218 A1	10-2005	Clark et al.	430/270.1
*	K	US-2005/0281982 A1	12-2005	Li, Shunpu	428/141
*	L	US-2006/0035164 A1	02-2006	Schaper, Charles Daniel	430/200
*	M	US-7,060,625 B2	06-2006	Lee, Heon	438/702

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/534,931		Applicant(s)/Patent Under Reexamination LI, SHUNPU	
	Examiner DAVID N. BROWN II		Art Unit 1791	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,136,150 B2	11-2006	Sreenivasan et al.	355/75
*	B	US-7,374,968 B2	05-2008	Kornilovich et al.	438/110
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.